S arch Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/415,295	BEN-EFRAIM ET AL.	
Examiner	Art Unit	
Khanh Dinh	2151	

SEARCHED					
Class	Subclass	Date	Examiner		
709	203, 224, 228	5/26/2006	KD		
455	414.1 413	5/26/2006	KD		
725	86	5/26/2006	KD		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
709	203, 224,	5/26/2006	KD	
455	413	5/26/2006	KD	
725	86	5/26/2006	KD	

SEARCH (INCLUDING SEAF		()
	DATE	EXMR
u polated WEST, IEEE, EPO, NPL	5/26/2006	KD